The two events are independent if any one of the following equivalent statetements is true:

- () P(AIB)=PlA)
- DP(BIA)=P(B)
- 3) P(AnB)= P(A).P(B)

Ex Suppose a day's production of 860 monufactured parts contains 50 ports that 20 not meet customer requirements. Suppose two parts are selected from the batch, but the first port is replaced before the second port is selected. What is the probability that the second port is defective (denoted as B) given that the first port is defective (denoted as A)? The probability needed can be expressed as P(B)A).

Because the first pot is replaced power to selecting the second port, the batch still contains 850 pots, of which 50 one defective. Therefore, the prob. of B does not defective or not the first port was defective. depend on whether or not the first port was defective. P(B|A) = P(B) = 50/850

The prob. of both pots are dejective is  $P(A \cap B) = P(B|A) \cdot P(A)$   $= P(B) \cdot P(A) = \frac{50}{850} \cdot \frac{50}{850} = 0.0035$ 

Control of the Contro			Alexander of the second	
	Yes(event F)		No	Total
Defective	Yes (event)	2	18	20
	No	38.	342	380
	Total	40	360	400

P(DIP) = 2/40 = 0.05 and P(D) = 20/400 = 0.05

That is, the probability that the part is dejective does not depend on whether it has surface flaws.

P(FID) = 2/20 = 0.10 end P(F) = 40/400 = 0.10

-) So, the prob. of a surface flow does not depend on whether the part is defective.

$$P(F \cap D) = P(D|F), P(F) = P(D), P(F)$$

$$= \frac{2}{40} \cdot \frac{2}{70} = \frac{1}{700}$$

## P(ADB) = P(BIA) . P(A) = P(AIB). P(B)

Ex: The prob. that an automobile battery subject to high engine compartment temperature suffers low charping current is 0.7. The prob. that a battery is subject to high eighte comportment temperature is 0.05.

Let C denote the event that a bottery suffers low Changing current, and let T denote the event that a battery is subject to high eyene comportment temperature.

The probability that a battery is subject to low Charging current and high engine comportment temperature is P(CNT) = P(CIT). P(T) = 0.7 x0.05 = 0.035

Ex: We have 3 green and 2 red balls in a bag. We gick balls one by one till we find a red ball. What is the probe that we don't pick more than 2 balls? (Finding the red on the first on second total)

P(Finding at first) = 2

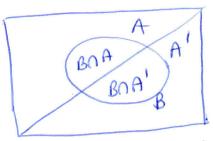
P(Finding at second) = P(First green, second red) =P(G, NRz) = P(G,1. P(Rz|G1)

= 3. 2 = 3. 2 = 30 > 4 balls left after picking one

P(Finding the red on the first or second) = = = = == == == ==

(From the lecture notes of H.S. Soroh and B. AYTAGOGUI)

For any two events A and B,



 $B \cap A'$   $B \cap A'$  B

Partitioning on event into two numbrally exclusive subsets.

Because A and A'are muhially exclusive, ANB and A'NB are also muhially exclusive.

Example: Suppose that in seniconductor manufacturing the probability is 0.10 that a chip that is subjected to high levels of contournation during monufacting causes a product failure. The probability is 0.005 that a chip that is not subjected to high contamination levels during manufacturing causes a product

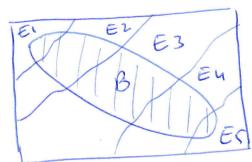
failure. In a particular production run, 20% of the chips are subject to high levels of contournation, What is the probability that a product using one of these chips falls?

Let F denote the event that the product fails, let H denote the event that the chip is exposed to high levels of contembor. The requested probability is P(F).

P(F|H|=0.10 and P(F|H')=0.005 P(H)=0.20 and P(H')=0.80

Then;

P(F) = P(F(H), P(F)+P(F(H)), P(H)) =0.10x0,20+0.009x0.80 =0.0235



B=(BnEi)U(BnEz)U(BnEz)U(BnEu)U(BnEr)
Porthoning on event into several numberally exclusive subsets.

Assume EI, Ez, ..., Ex are k muhally exclusive and exhaustive sets. Then,

P(B) = P(BNE) + P(BNEZ) + ... + P(BNEL) = P(B) = P(B) = 1. P(E) + P(B) = 2). P(E) + ... + P(B) = u). P(Eu)

Example: Semiconductor manufacturity, example, assume the following probabilities for product failure subject to levels of contembors in manufacturity.

Probability Level of Contemption

0.10

High

0.01

Medium

Jaw

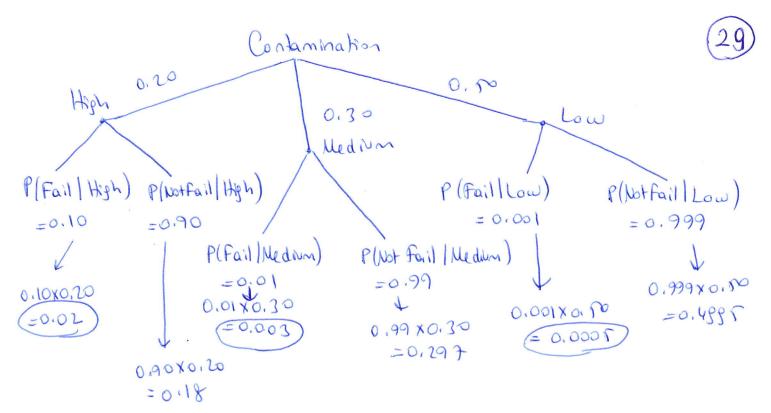
In a particular run, 20% of the chips are subjected to high levels of contamination, 30% to medium levels of contamination, and 70% to low levels of contamination. What is the probability that a product using one of these chips falls?

H-) event that a chip is exposed to high levels of contentination.
M-) " " nedwm " "

Lande to the terms of low the terms

Then,  $P(F) = P(F|H) \cdot P(H) + P(F|M) \cdot P(M) + P(F|M) \cdot P(L)$ 

= 0.10x0,20+0.01x0,30 +0.001x0, 00=0.0235/



## Bayes Theorem

If E, Ez, ..., Ex ore k mutually and exhaustive events and B is any event,

$$P(E_1|B) = \frac{P(B|E_1).P(E_1)}{P(E_1|B_1)}$$

P(BIEI). P(E) + P(BIEZ). P(EZ) + ... + P(BIEN). P(EN)

If we deal with n events (E, Ez, ..., En)
$$P(Ek|B) = \frac{P(B|Ek).P(En)}{\sum_{j=1}^{n} P(B|E_j).P(E_j)}, P(B) > 0.$$

Ex Only one in 1000 adults is afflicted with a none disease for 30 which a diagnostic test has been developed. We know that

P(Test result is "+" | Md. has the disease) = 0.99 Pl Test result is "+" | ind. has no disease) = 0.02

If a randomly selected individual is tested and the test is possible what is the probability that the individual has the disease?

P(Ind. has disease | Test is "+")=?

D > the event that you have the illness.

S-) " " the test result is possitive.

P(DIS)=?

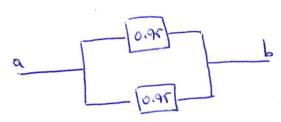
 $P(D|S) = \frac{P(D\cap S)}{P(S)} = \frac{P(S|D).P(D)}{P(S)}$ 

 $P(S) = P(S \cap D) + P(S \cap D')$ = P(SID).P(D) + P(SID').P(D') = 0.99 x 0.001 + 0.02 x 0.999 = 0.02097

Then,

 $P[D|S] = \frac{0.99 \times 0.001}{0.02097} = \frac{0.00099}{0.02097} = 0.047$ 

Example: The following circuit operates of there is a path of functional devices from left to right. The probability that each device functions is shown on the proph. Assume that devices fail independently. What is the probability that the circuit operates!



Let T and B denote the events that the top and bottom devices operate, respectively. There is a path if at least one device operator. The prob. that the chrait operates is;

Example

Lievent that left device operates
Rim " right "

If both operates, system operates so;

P[Lond R] - prob-that the circuit opendes